

Notice of References Cited	Application/Control No. 10/699,780		Applicant(s)/Patent Under Reexamination FENG ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,010,541	01-2000	de la Mettrie et al.	8/412
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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FOREIGN PATENT DOCUMENTS

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